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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	2880
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	113
Number of Gates	48000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx32a-ftqg144

JTAG Instructions

Table 1-7 lists the supported instructions with the corresponding IR codes for SX-A devices.

Table 1-8 lists the codes returned after executing the IDCODE instruction for SX-A devices. Note that bit 0 is always '1'. Bits 11-1 are always '02F', which is the Actel manufacturer code.

Table 1-7 • JTAG Instruction Code

Instructions (IR4:IR0)	Binary Code
EXTEST	00000
SAMPLE/PRELOAD	00001
INTTEST	00010
USERCODE	00011
IDCODE	00100
HighZ	01110
CLAMP	01111
Diagnostic	10000
BYPASS	11111
Reserved	All others

Table 1-8 • JTAG Instruction Code

Device	Process	Revision	Bits 31-28	Bits 27-12
A54SX08A	0.22 μ	0	8, 9	40B4, 42B4
		1	A, B	40B4, 42B4
A54SX16A	0.22 μ	0	9	40B8, 42B8
		1	B	40B8, 42B8
	0.25 μ	1	B	22B8
A54SX32A	0.2 2 μ	0	9	40BD, 42BD
		1	B	40BD, 42BD
	0.25 μ	1	B	22BD
A54SX72A	0.22 μ	0	9	40B2, 42B2
		1	B	40B2, 42B2
	0.25 μ	1	B	22B2

Pin Description

CLKA/B, I/O **Clock A and B**

These pins are clock inputs for clock distribution networks. Input levels are compatible with standard TTL, LVTTTL, LVCMOS2, 3.3 V PCI, or 5 V PCI specifications. The clock input is buffered prior to clocking the R-cells. When not used, this pin must be tied Low or High (NOT left floating) on the board to avoid unwanted power consumption.

For A54SX72A, these pins can also be configured as user I/Os. When employed as user I/Os, these pins offer built-in programmable pull-up or pull-down resistors active during power-up only. When not used, these pins must be tied Low or High (NOT left floating).

QCLKA/B/C/D, I/O **Quadrant Clock A, B, C, and D**

These four pins are the quadrant clock inputs and are only used for A54SX72A with A, B, C, and D corresponding to bottom-left, bottom-right, top-left, and top-right quadrants, respectively. They are clock inputs for clock distribution networks. Input levels are compatible with standard TTL, LVTTTL, LVCMOS2, 3.3 V PCI, or 5 V PCI specifications. Each of these clock inputs can drive up to a quarter of the chip, or they can be grouped together to drive multiple quadrants. The clock input is buffered prior to clocking the R-cells. When not used, these pins must be tied Low or High on the board (NOT left floating).

These pins can also be configured as user I/Os. When employed as user I/Os, these pins offer built-in programmable pull-up or pull-down resistors active during power-up only.

GND **Ground**

Low supply voltage.

HCLK **Dedicated (Hardwired) Array Clock**

This pin is the clock input for sequential modules. Input levels are compatible with standard TTL, LVTTTL, LVCMOS2, 3.3 V PCI, or 5 V PCI specifications. This input is directly wired to each R-cell and offers clock speeds independent of the number of R-cells being driven. When not used, HCLK must be tied Low or High on the board (NOT left floating). When used, this pin should be held Low or High during power-up to avoid unwanted static power consumption.

I/O **Input/Output**

The I/O pin functions as an input, output, tristate, or bidirectional buffer. Based on certain configurations, input and output levels are compatible with standard TTL, LVTTTL, LVCMOS2, 3.3 V PCI or 5 V PCI specifications. Unused I/O pins are automatically tristated by the Designer software.

NC **No Connection**

This pin is not connected to circuitry within the device and can be driven to any voltage or be left floating with no effect on the operation of the device.

PRA/B, I/O **Probe A/B**

The Probe pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the other probe pin to allow real-time diagnostic output of any signal path within the device. The Probe pin can be used as a user-defined I/O when verification has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality.

TCK, I/O **Test Clock**

Test clock input for diagnostic probe and device programming. In Flexible mode, TCK becomes active when the TMS pin is set Low (refer to Table 1-6 on page 1-9). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.

TDI, I/O **Test Data Input**

Serial input for boundary scan testing and diagnostic probe. In Flexible mode, TDI is active when the TMS pin is set Low (refer to Table 1-6 on page 1-9). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.

TDO, I/O **Test Data Output**

Serial output for boundary scan testing. In flexible mode, TDO is active when the TMS pin is set Low (refer to Table 1-6 on page 1-9). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state. When Silicon Explorer II is being used, TDO will act as an output when the checksum command is run. It will return to user I/O when checksum is complete.

TMS **Test Mode Select**

The TMS pin controls the use of the IEEE 1149.1 Boundary Scan pins (TCK, TDI, TDO, TRST). In flexible mode when the TMS pin is set Low, the TCK, TDI, and TDO pins are boundary scan pins (refer to Table 1-6 on page 1-9). Once the boundary scan pins are in test mode, they will remain in that mode until the internal boundary scan state machine reaches the logic reset state. At this point, the boundary scan pins will be released and will function as regular I/O pins. The logic reset state is reached five TCK cycles after the TMS pin is set High. In dedicated test mode, TMS functions as specified in the IEEE 1149.1 specifications.

TRST, I/O **Boundary Scan Reset Pin**

Once it is configured as the JTAG Reset pin, the TRST pin functions as an active low input to asynchronously initialize or reset the boundary scan circuit. The TRST pin is equipped with an internal pull-up resistor. This pin functions as an I/O when the **Reserve JTAG Reset Pin** is not selected in Designer.

V_{CC} **Supply Voltage**

Supply voltage for I/Os. See Table 2-2 on page 2-1. All V_{CC} power pins in the device should be connected.

V_{CCA} **Supply Voltage**

Supply voltage for array. See Table 2-2 on page 2-1. All V_{CCA} power pins in the device should be connected.

Electrical Specifications

Table 2-5 • 3.3 V LVTTTL and 5 V TTL Electrical Specifications

Symbol	Parameter		Commercial		Industrial		Units
			Min.	Max.	Min.	Max.	
V _{OH}	V _{CCI} = Minimum V _I = V _{IH} or V _{IL}	(I _{OH} = −1 mA)	0.9 V _{CCI}		0.9 V _{CCI}		V
	V _{CCI} = Minimum V _I = V _{IH} or V _{IL}	(I _{OH} = −8 mA)	2.4		2.4		V
V _{OL}	V _{CCI} = Minimum V _I = V _{IH} or V _{IL}	(I _{OL} = 1 mA)	0.4		0.4		V
	V _{CCI} = Minimum V _I = V _{IH} or V _{IL}	(I _{OL} = 12 mA)	0.4		0.4		V
V _{IL}	Input Low Voltage		0.8		0.8		V
V _{IH}	Input High Voltage		2.0	5.75	2.0	5.75	V
I _{IL} /I _{IH}	Input Leakage Current, V _{IN} = V _{CCI} or GND		−10	10	−10	10	μA
I _{OZ}	Tristate Output Leakage Current		−10	10	−10	10	μA
t _R , t _F	Input Transition Time t _R , t _F		10		10		ns
C _{IO}	I/O Capacitance		10		10		pF
I _{CC}	Standby Current		10		20		mA
IV Curve*	Can be derived from the IBIS model on the web.						

Note: *The IBIS model can be found at <http://www.actel.com/download/libis/default.aspx>.

Table 2-6 • 2.5 V LVCMOS2 Electrical Specifications

Symbol	Parameter		Commercial		Industrial		Units
			Min.	Max.	Min.	Max.	
V _{OH}	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OH} = -100 μA)	2.1		2.1		V
	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OH} = -1 mA)	2.0		2.0		V
	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OH} = -2 mA)	1.7		1.7		V
V _{OL}	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OL} = 100 μA)		0.2		0.2	V
	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OL} = 1 mA)		0.4		0.4	V
	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OL} = 2 mA)		0.7		0.7	V
V _{IL}	Input Low Voltage, V _{OUT} ≤ V _{VOL(max)}		-0.3	0.7	-0.3	0.7	V
V _{IH}	Input High Voltage, V _{OUT} ≥ V _{VOH(min)}		1.7	5.75	1.7	5.75	V
I _{IL} /I _{IH}	Input Leakage Current, V _{IN} = V _{CCI} or GND		-10	10	-10	10	μA
I _{OZ}	Tristate Output Leakage Current, V _{OUT} = V _{CCI} or GND		-10	10	-10	10	μA
t _R , t _F	Input Transition Time t _R , t _F			10		10	ns
C _{IO}	I/O Capacitance			10		10	pF
I _{CC}	Standby Current			10		20	mA
IV Curve*	Can be derived from the IBIS model on the web.						

Note: *The IBIS model can be found at <http://www.actel.com/download/libis/default.aspx>.

PCI Compliance for the SX-A Family

The SX-A family supports 3.3 V and 5 V PCI and is compliant with the PCI Local Bus Specification Rev. 2.1.

Table 2-7 • DC Specifications (5 V PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
V _{CCA}	Supply Voltage for Array		2.25	2.75	V
V _{CCI}	Supply Voltage for I/Os		4.75	5.25	V
V _{IH}	Input High Voltage		2.0	5.75	V
V _{IL}	Input Low Voltage		–0.5	0.8	V
I _{IH}	Input High Leakage Current ¹	V _{IN} = 2.7	–	70	μA
I _{IL}	Input Low Leakage Current ¹	V _{IN} = 0.5	–	–70	μA
V _{OH}	Output High Voltage	I _{OUT} = –2 mA	2.4	–	V
V _{OL}	Output Low Voltage ²	I _{OUT} = 3 mA, 6 mA	–	0.55	V
C _{IN}	Input Pin Capacitance ³		–	10	pF
C _{CLK}	CLK Pin Capacitance		5	12	pF

Notes:

1. Input leakage currents include hi-Z output leakage for all bidirectional buffers with tristate outputs.
2. Signals without pull-up resistors must have 3 mA low output current. Signals requiring pull-up must have 6 mA; the latter includes FRAME#, IRDY#, TRDY#, DEVSEL#, STOP#, SERR#, PERR#, LOCK#, and, when used AD[63::32], C/BE[7::4]#, PAR64, REQ64#, and ACK64#.
3. Absolute maximum pin capacitance for a PCI input is 10 pF (except for CLK).

Theta-JA

Junction-to-ambient thermal resistance (θ_{JA}) is determined under standard conditions specified by JESD-51 series but has little relevance in actual performance of the product in real application. It should be employed with caution but is useful for comparing the thermal performance of one package to another.

A sample calculation to estimate the absolute maximum power dissipation allowed (worst case) for a 329-pin PBGA package at still air is as follows. i.e.:

$$\theta_{JA} = 17.1^{\circ}\text{C/W} \text{ is taken from Table 2-12 on page 2-11}$$

$$T_A = 125^{\circ}\text{C} \text{ is the maximum limit of ambient (from the datasheet)}$$

$$\text{Max. Allowed Power} = \frac{\text{Max Junction Temp} - \text{Max. Ambient Temp}}{\theta_{JA}} = \frac{150^{\circ}\text{C} - 125^{\circ}\text{C}}{17.1^{\circ}\text{C/W}} = 1.46 \text{ W}$$

EQ 2-11

The device's power consumption must be lower than the calculated maximum power dissipation by the package.

The power consumption of a device can be calculated using the Actel power calculator. If the power consumption is higher than the device's maximum allowable power dissipation, then a heat sink can be attached on top of the case or the airflow inside the system must be increased.

Theta-JC

Junction-to-case thermal resistance (θ_{JC}) measures the ability of a device to dissipate heat from the surface of the chip to the top or bottom surface of the package. It is applicable for packages used with external heat sinks and only applies to situations where all or nearly all of the heat is dissipated through the surface in consideration. If the power consumption is higher than the calculated maximum power dissipation of the package, then a heat sink is required.

Calculation for Heat Sink

For example, in a design implemented in a FG484 package, the power consumption value using the power calculator is 3.00 W. The user-dependent data T_J and T_A are given as follows:

$$T_J = 110^{\circ}\text{C}$$

$$T_A = 70^{\circ}\text{C}$$

From the datasheet:

$$\theta_{JA} = 18.0^{\circ}\text{C/W}$$

$$\theta_{JC} = 3.2^{\circ}\text{C/W}$$

$$P = \frac{\text{Max Junction Temp} - \text{Max. Ambient Temp}}{\theta_{JA}} = \frac{110^{\circ}\text{C} - 70^{\circ}\text{C}}{18.0^{\circ}\text{C/W}} = 2.22 \text{ W}$$

EQ 2-12

The 2.22 W power is less than then required 3.00 W; therefore, the design requires a heat sink or the airflow where the device is mounted should be increased. The design's junction-to-air thermal resistance requirement can be estimated by:

$$\theta_{JA} = \frac{\text{Max Junction Temp} - \text{Max. Ambient Temp}}{P} = \frac{110^{\circ}\text{C} - 70^{\circ}\text{C}}{3.00 \text{ W}} = 13.33^{\circ}\text{C/W}$$

EQ 2-13

Timing Characteristics

Table 2-14 • A54SX08A Timing Characteristics
(Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays ¹										
t _{PD}	Internal Array Module	0.9		1.1		1.2		1.7		ns
Predicted Routing Delays ²										
t _{DC}	FO = 1 Routing Delay, Direct Connect	0.1		0.1		0.1		0.1		ns
t _{FC}	FO = 1 Routing Delay, Fast Connect	0.3		0.3		0.4		0.6		ns
t _{RD1}	FO = 1 Routing Delay	0.3		0.4		0.5		0.6		ns
t _{RD2}	FO = 2 Routing Delay	0.5		0.5		0.6		0.8		ns
t _{RD3}	FO = 3 Routing Delay	0.6		0.7		0.8		1.1		ns
t _{RD4}	FO = 4 Routing Delay	0.8		0.9		1		1.4		ns
t _{RD8}	FO = 8 Routing Delay	1.4		1.5		1.8		2.5		ns
t _{RD12}	FO = 12 Routing Delay	2		2.2		2.6		3.6		ns
R-Cell Timing										
t _{RCO}	Sequential Clock-to-Q	0.7		0.8		0.9		1.3		ns
t _{CLR}	Asynchronous Clear-to-Q	0.6		0.6		0.8		1.0		ns
t _{PRESET}	Asynchronous Preset-to-Q	0.7		0.7		0.9		1.2		ns
t _{SUD}	Flip-Flop Data Input Set-Up	0.7		0.8		0.9		1.2		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	1.4		1.5		1.8		2.5		ns
t _{RECASYN}	Asynchronous Recovery Time	0.4		0.4		0.5		0.7		ns
t _{HASYN}	Asynchronous Hold Time	0.3		0.3		0.4		0.6		ns
t _{MPW}	Clock Pulse Width	1.6		1.8		2.1		2.9		ns
Input Module Propagation Delays										
t _{INYH}	Input Data Pad to Y High 2.5 V LVCMOS	0.8		0.9		1.0		1.4		ns
t _{INYL}	Input Data Pad to Y Low 2.5 V LVCMOS	1.0		1.2		1.4		1.9		ns
t _{INYH}	Input Data Pad to Y High 3.3 V PCI	0.6		0.6		0.7		1.0		ns
t _{INYL}	Input Data Pad to Y Low 3.3 V PCI	0.7		0.8		0.9		1.3		ns
t _{INYH}	Input Data Pad to Y High 3.3 V LVTTTL	0.7		0.7		0.9		1.2		ns
t _{INYL}	Input Data Pad to Y Low 3.3 V LVTTTL	1.0		1.1		1.3		1.8		ns

Notes:

- For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-16 • A54SX08A Timing Characteristics

(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks										
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.3		1.5		1.7		2.6	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.1		1.3		1.5		2.2	ns
t _{HPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{HPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{HCKSW}	Maximum Skew		0.4		0.5		0.5		0.8	ns
t _{HP}	Minimum Period	3.2		3.6		4.2		5.8		ns
f _{HMAX}	Maximum Frequency		313		278		238		172	MHz
Routed Array Clock Networks										
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		0.8		0.9		1.1		1.5	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.1		1.2		1.4		2	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		0.8		0.9		1.1		1.5	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.1		1.2		1.4		2	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.1		1.2		1.4		1.9	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.2		1.3		1.6		2.2	ns
t _{RPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{RPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{RCKSW}	Maximum Skew (Light Load)		0.7		0.8		0.9		1.3	ns
t _{RCKSW}	Maximum Skew (50% Load)		0.7		0.8		0.9		1.3	ns
t _{RCKSW}	Maximum Skew (100% Load)		0.8		0.9		1.1		1.5	ns

Table 2-17 • **A54SX08A Timing Characteristics**
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks										
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.2		1.3		1.5		2.3	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.0		1.2		1.4		2.0	ns
t _{HPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{HPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{HCKSW}	Maximum Skew		0.4		0.4		0.5		0.8	ns
t _{HP}	Minimum Period	3.2		3.6		4.2		5.8		ns
f _{HMAX}	Maximum Frequency		313		278		238		172	MHz
Routed Array Clock Networks										
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		0.9		1.0		1.2		1.7	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.5		1.7		2.0		2.7	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		0.9		1.0		1.2		1.7	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.5		1.7		2.0		2.7	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.1		1.3		1.5		2.1	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.6		1.8		2.1		2.9	ns
t _{RPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{RPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{RCKSW}	Maximum Skew (Light Load)		0.8		0.9		1.1		1.5	ns
t _{RCKSW}	Maximum Skew (50% Load)		0.8		1.0		1.1		1.5	ns
t _{RCKSW}	Maximum Skew (100% Load)		0.9		1.0		1.2		1.7	ns

Table 2-20 • A54SX08A Timing Characteristics

(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
5 V PCI Output Module Timing ¹										
t _{DLH}	Data-to-Pad Low to High		2.4		2.8		3.2		4.5	ns
t _{DHL}	Data-to-Pad High to Low		3.2		3.6		4.2		5.9	ns
t _{ENZL}	Enable-to-Pad, Z to L		1.5		1.7		2.0		2.8	ns
t _{ENZH}	Enable-to-Pad, Z to H		2.4		2.8		3.2		4.5	ns
t _{ENLZ}	Enable-to-Pad, L to Z		3.5		3.9		4.6		6.4	ns
t _{ENHZ}	Enable-to-Pad, H to Z		3.2		3.6		4.2		5.9	ns
d _{TLH} ²	Delta Low to High		0.016		0.02		0.022		0.032	ns/pF
d _{THL} ²	Delta High to Low		0.03		0.032		0.04		0.052	ns/pF
5 V TTL Output Module Timing ³										
t _{DLH}	Data-to-Pad Low to High		2.4		2.8		3.2		4.5	ns
t _{DHL}	Data-to-Pad High to Low		3.2		3.6		4.2		5.9	ns
t _{DHLS}	Data-to-Pad High to Low—low slew		7.6		8.6		10.1		14.2	ns
t _{ENZL}	Enable-to-Pad, Z to L		2.4		2.7		3.2		4.5	ns
t _{ENZLS}	Enable-to-Pad, Z to L—low slew		8.4		9.5		11.0		15.4	ns
t _{ENZH}	Enable-to-Pad, Z to H		2.4		2.8		3.2		4.5	ns
t _{ENLZ}	Enable-to-Pad, L to Z		4.2		4.7		5.6		7.8	ns
t _{ENHZ}	Enable-to-Pad, H to Z		3.2		3.6		4.2		5.9	ns
d _{TLH}	Delta Low to High		0.017		0.017		0.023		0.031	ns/pF
d _{THL}	Delta High to Low		0.029		0.031		0.037		0.051	ns/pF
d _{THLS}	Delta High to Low—low slew		0.046		0.057		0.066		0.089	ns/pF

Notes:

- Delays based on 50 pF loading.
- To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[HL|HL|HLS]})$$
where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[HL|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
- Delays based on 35 pF loading.

Table 2-22 • **A54SX16A Timing Characteristics**
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.25\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks												
t _{HCKH}	Input Low to High (Pad to R-cell Input)	1.2		1.4		1.6		1.8		2.8		ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)	1.0		1.1		1.2		1.5		2.2		ns
t _{HPWH}	Minimum Pulse Width High	1.4		1.7		1.9		2.2		3.0		ns
t _{HPWL}	Minimum Pulse Width Low	1.4		1.7		1.9		2.2		3.0		ns
t _{HCKSW}	Maximum Skew	0.3		0.3		0.4		0.4		0.7		ns
t _{HP}	Minimum Period	2.8		3.4		3.8		4.4		6.0		ns
f _{HMAX}	Maximum Frequency	357		294		263		227		167		MHz
Routed Array Clock Networks												
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)	1.0		1.2		1.3		1.6		2.2		ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)	1.1		1.3		1.5		1.7		2.4		ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)	1.1		1.3		1.5		1.7		2.4		ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)	1.1		1.3		1.5		1.7		2.4		ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)	1.3		1.5		1.7		2.0		2.8		ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)	1.3		1.5		1.7		2.0		2.8		ns
t _{RPWH}	Minimum Pulse Width High	1.4		1.7		1.9		2.2		3.0		ns
t _{RPWL}	Minimum Pulse Width Low	1.4		1.7		1.9		2.2		3.0		ns
t _{RCKSW}	Maximum Skew (Light Load)	0.8		0.9		1.0		1.2		1.7		ns
t _{RCKSW}	Maximum Skew (50% Load)	0.8		0.9		1.0		1.2		1.7		ns
t _{RCKSW}	Maximum Skew (100% Load)	1.0		1.1		1.3		1.5		2.1		ns

Note: *All –3 speed grades have been discontinued.

Table 2-25 • A54SX16A Timing Characteristics

(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.25\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed ¹		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
2.5 V LVCMOS Output Module Timing ^{2, 3}												
t _{DLH}	Data-to-Pad Low to High		3.4		3.9		4.5		5.2		7.3	ns
t _{DHL}	Data-to-Pad High to Low		2.6		3.0		3.3		3.9		5.5	ns
t _{DHLS}	Data-to-Pad High to Low—low slew		11.6		13.4		15.2		17.9		25.0	ns
t _{ENZL}	Enable-to-Pad, Z to L		2.4		2.8		3.2		3.7		5.2	ns
t _{ENZLS}	Data-to-Pad, Z to L—low slew		11.8		13.7		15.5		18.2		25.5	ns
t _{ENZH}	Enable-to-Pad, Z to H		3.4		3.9		4.5		5.2		7.3	ns
t _{ENLZ}	Enable-to-Pad, L to Z		2.1		2.5		2.8		3.3		4.7	ns
t _{ENHZ}	Enable-to-Pad, H to Z		2.6		3.0		3.3		3.9		5.5	ns
d _{TLH} ⁴	Delta Low to High		0.031		0.037		0.043		0.051		0.071	ns/pF
d _{THL} ⁴	Delta High to Low		0.017		0.017		0.023		0.023		0.037	ns/pF
d _{THLS} ⁴	Delta High to Low—low slew		0.057		0.06		0.071		0.086		0.117	ns/pF

Note:

1. All –3 speed grades have been discontinued.
2. Delays based on 35 pF loading.
3. The equivalent IO Attribute settings for 2.5 V LVCMOS is 2.5 V LVTTTL in the software.
4. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$$
where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

Table 2-26 • **A54SX16A Timing Characteristics**
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed ¹		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
3.3 V PCI Output Module Timing ²												
t _{DLH}	Data-to-Pad Low to High		2.0		2.3		2.6		3.1		4.3	ns
t _{DHL}	Data-to-Pad High to Low		2.2		2.5		2.8		3.3		4.6	ns
t _{ENZL}	Enable-to-Pad, Z to L		1.4		1.7		1.9		2.2		3.1	ns
t _{ENZH}	Enable-to-Pad, Z to H		2.0		2.3		2.6		3.1		4.3	ns
t _{ENLZ}	Enable-to-Pad, L to Z		2.5		2.8		3.2		3.8		5.3	ns
t _{ENHZ}	Enable-to-Pad, H to Z		2.2		2.5		2.8		3.3		4.6	ns
d _{TLH} ³	Delta Low to High		0.025		0.03		0.03		0.04		0.045	ns/pF
d _{THL} ³	Delta High to Low		0.015		0.015		0.015		0.015		0.025	ns/pF
3.3 V LVTTTL Output Module Timing ⁴												
t _{DLH}	Data-to-Pad Low to High		2.8		3.2		3.6		4.3		6.0	ns
t _{DHL}	Data-to-Pad High to Low		2.7		3.1		3.5		4.1		5.7	ns
t _{DHLS}	Data-to-Pad High to Low—low slew		9.5		10.9		12.4		14.6		20.4	ns
t _{ENZL}	Enable-to-Pad, Z to L		2.2		2.6		2.9		3.4		4.8	ns
t _{ENZLS}	Enable-to-Pad, Z to L—low slew		15.8		18.9		21.3		25.4		34.9	ns
t _{ENZH}	Enable-to-Pad, Z to H		2.8		3.2		3.6		4.3		6.0	ns
t _{ENLZ}	Enable-to-Pad, L to Z		2.9		3.3		3.7		4.4		6.2	ns
t _{ENHZ}	Enable-to-Pad, H to Z		2.7		3.1		3.5		4.1		5.7	ns
d _{TLH} ³	Delta Low to High		0.025		0.03		0.03		0.04		0.045	ns/pF
d _{THL} ³	Delta High to Low		0.015		0.015		0.015		0.015		0.025	ns/pF
d _{THLS} ³	Delta High to Low—low slew		0.053		0.053		0.067		0.073		0.107	ns/pF

Notes:

1. All –3 speed grades have been discontinued.
2. Delays based on 10 pF loading and 25 Ω resistance.
3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$$
 where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. Delays based on 35 pF loading.

Table 2-31 • **A54SX32A Timing Characteristics**
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks												
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.7		1.9		2.2		2.6		4.0	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.7		2.0		2.2		2.6		4.0	ns
t _{HPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns
t _{HPWL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns
t _{HCKSW}	Maximum Skew		0.6		0.6		0.7		0.8		1.3	ns
t _{HP}	Minimum Period	2.8		3.2		3.6		4.2		5.8		ns
f _{HMAX}	Maximum Frequency		357		313		278		238		172	MHz
Routed Array Clock Networks												
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		2.2		2.5		2.8		3.3		4.7	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		2.1		2.5		2.8		3.3		4.5	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		2.4		2.7		3.1		3.6		5.1	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		2.2		2.6		2.9		3.4		4.7	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		2.5		2.8		3.2		3.8		5.3	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		2.4		2.8		3.1		3.7		5.2	ns
t _{RPWH}	Minimum Pulse Width High	1.4		1.6		1.8		2.1		2.9		ns
t _{RPWL}	Minimum Pulse Width Low	1.4		1.6		1.8		2.1		2.9		ns
t _{RCKSW}	Maximum Skew (Light Load)		1.0		1.1		1.3		1.5		2.1	ns
t _{RCKSW}	Maximum Skew (50% Load)		1.0		1.1		1.3		1.5		2.1	ns
t _{RCKSW}	Maximum Skew (100% Load)		1.0		1.1		1.3		1.5		2.1	ns

Note: *All –3 speed grades have been discontinued.

Table 2-32 • A54SX32A Timing Characteristics

(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.3\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed ¹		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
2.5 V LVCMOS Output Module Timing ^{2,3}												
t _{DLH}	Data-to-Pad Low to High		3.3		3.8		4.2		5.0		7.0	ns
t _{DHL}	Data-to-Pad High to Low		2.5		2.9		3.2		3.8		5.3	ns
t _{DHLS}	Data-to-Pad High to Low—low slew		11.1		12.8		14.5		17.0		23.8	ns
t _{ENZL}	Enable-to-Pad, Z to L		2.4		2.8		3.2		3.7		5.2	ns
t _{ENZLS}	Data-to-Pad, Z to L—low slew		11.8		13.7		15.5		18.2		25.5	ns
t _{ENZH}	Enable-to-Pad, Z to H		3.3		3.8		4.2		5.0		7.0	ns
t _{ENLZ}	Enable-to-Pad, L to Z		2.1		2.5		2.8		3.3		4.7	ns
t _{ENHZ}	Enable-to-Pad, H to Z		2.5		2.9		3.2		3.8		5.3	ns
d _{TLH} ⁴	Delta Low to High		0.031		0.037		0.043		0.051		0.071	ns/pF
d _{THL} ⁴	Delta High to Low		0.017		0.017		0.023		0.023		0.037	ns/pF
d _{THLS} ⁴	Delta High to Low—low slew		0.057		0.06		0.071		0.086		0.117	ns/pF

Note:

1. All –3 speed grades have been discontinued.
2. Delays based on 35 pF loading.
3. The equivalent IO Attribute settings for 2.5 V LVCMOS is 2.5 V LVTTTL in the software.
4. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$$
where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

Table 2-40 • A54SX72A Timing Characteristics
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed ¹		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
3.3 V PCI Output Module Timing ²												
t _{DLH}	Data-to-Pad Low to High	2.3		2.7		3.0		3.6		5.0		ns
t _{DHL}	Data-to-Pad High to Low	2.5		2.9		3.2		3.8		5.3		ns
t _{ENZL}	Enable-to-Pad, Z to L	1.4		1.7		1.9		2.2		3.1		ns
t _{ENZH}	Enable-to-Pad, Z to H	2.3		2.7		3.0		3.6		5.0		ns
t _{ENLZ}	Enable-to-Pad, L to Z	2.5		2.8		3.2		3.8		5.3		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.5		2.9		3.2		3.8		5.3		ns
d _{TLH} ³	Delta Low to High	0.025		0.03		0.03		0.04		0.045		ns/pF
d _{THL} ³	Delta High to Low	0.015		0.015		0.015		0.015		0.025		ns/pF
3.3 V LVTTTL Output Module Timing ⁴												
t _{DLH}	Data-to-Pad Low to High	3.2		3.7		4.2		5.0		6.9		ns
t _{DHL}	Data-to-Pad High to Low	3.2		3.7		4.2		4.9		6.9		ns
t _{DHLS}	Data-to-Pad High to Low—low slew	10.3		11.9		13.5		15.8		22.2		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.2		2.6		2.9		3.4		4.8		ns
t _{ENZLS}	Enable-to-Pad, Z to L—low slew	15.8		18.9		21.3		25.4		34.9		ns
t _{ENZH}	Enable-to-Pad, Z to H	3.2		3.7		4.2		5.0		6.9		ns
t _{ENLZ}	Enable-to-Pad, L to Z	2.9		3.3		3.7		4.4		6.2		ns
t _{ENHZ}	Enable-to-Pad, H to Z	3.2		3.7		4.2		4.9		6.9		ns
d _{TLH} ³	Delta Low to High	0.025		0.03		0.03		0.04		0.045		ns/pF
d _{THL} ³	Delta High to Low	0.015		0.015		0.015		0.015		0.025		ns/pF
d _{THLS} ³	Delta High to Low—low slew	0.053		0.053		0.067		0.073		0.107		ns/pF

Notes:

1. All –3 speed grades have been discontinued.
2. Delays based on 10 pF loading and 25 Ω resistance.
3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[HL|HL|HLS]})$$
 where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[HL|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. Delays based on 35 pF loading.

100-TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
71	I/O	I/O	I/O
72	I/O	I/O	I/O
73	I/O	I/O	I/O
74	I/O	I/O	I/O
75	I/O	I/O	I/O
76	I/O	I/O	I/O
77	I/O	I/O	I/O
78	I/O	I/O	I/O
79	I/O	I/O	I/O
80	I/O	I/O	I/O
81	I/O	I/O	I/O
82	V _{CCI}	V _{CCI}	V _{CCI}
83	I/O	I/O	I/O
84	I/O	I/O	I/O
85	I/O	I/O	I/O
86	I/O	I/O	I/O
87	CLKA	CLKA	CLKA
88	CLKB	CLKB	CLKB
89	NC	NC	NC
90	V _{CCA}	V _{CCA}	V _{CCA}
91	GND	GND	GND
92	PRA, I/O	PRA, I/O	PRA, I/O
93	I/O	I/O	I/O
94	I/O	I/O	I/O
95	I/O	I/O	I/O
96	I/O	I/O	I/O
97	I/O	I/O	I/O
98	I/O	I/O	I/O
99	I/O	I/O	I/O
100	TCK, I/O	TCK, I/O	TCK, I/O

144-Pin TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
75	I/O	I/O	I/O
76	I/O	I/O	I/O
77	I/O	I/O	I/O
78	I/O	I/O	I/O
79	V _{CCA}	V _{CCA}	V _{CCA}
80	V _{CCI}	V _{CCI}	V _{CCI}
81	GND	GND	GND
82	I/O	I/O	I/O
83	I/O	I/O	I/O
84	I/O	I/O	I/O
85	I/O	I/O	I/O
86	I/O	I/O	I/O
87	I/O	I/O	I/O
88	I/O	I/O	I/O
89	V _{CCA}	V _{CCA}	V _{CCA}
90	NC	NC	NC
91	I/O	I/O	I/O
92	I/O	I/O	I/O
93	I/O	I/O	I/O
94	I/O	I/O	I/O
95	I/O	I/O	I/O
96	I/O	I/O	I/O
97	I/O	I/O	I/O
98	V _{CCA}	V _{CCA}	V _{CCA}
99	GND	GND	GND
100	I/O	I/O	I/O
101	GND	GND	GND
102	V _{CCI}	V _{CCI}	V _{CCI}
103	I/O	I/O	I/O
104	I/O	I/O	I/O
105	I/O	I/O	I/O
106	I/O	I/O	I/O
107	I/O	I/O	I/O
108	I/O	I/O	I/O
109	GND	GND	GND
110	I/O	I/O	I/O

144-Pin TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
111	I/O	I/O	I/O
112	I/O	I/O	I/O
113	I/O	I/O	I/O
114	I/O	I/O	I/O
115	V _{CCI}	V _{CCI}	V _{CCI}
116	I/O	I/O	I/O
117	I/O	I/O	I/O
118	I/O	I/O	I/O
119	I/O	I/O	I/O
120	I/O	I/O	I/O
121	I/O	I/O	I/O
122	I/O	I/O	I/O
123	I/O	I/O	I/O
124	I/O	I/O	I/O
125	CLKA	CLKA	CLKA
126	CLKB	CLKB	CLKB
127	NC	NC	NC
128	GND	GND	GND
129	V _{CCA}	V _{CCA}	V _{CCA}
130	I/O	I/O	I/O
131	PRA, I/O	PRA, I/O	PRA, I/O
132	I/O	I/O	I/O
133	I/O	I/O	I/O
134	I/O	I/O	I/O
135	I/O	I/O	I/O
136	I/O	I/O	I/O
137	I/O	I/O	I/O
138	I/O	I/O	I/O
139	I/O	I/O	I/O
140	V _{CCI}	V _{CCI}	V _{CCI}
141	I/O	I/O	I/O
142	I/O	I/O	I/O
143	I/O	I/O	I/O
144	TCK, I/O	TCK, I/O	TCK, I/O

329-Pin PBGA	
Pin Number	A545X32A Function
V22	I/O
V23	I/O
W1	I/O
W2	I/O
W3	I/O
W4	I/O
W20	I/O
W21	I/O
W22	I/O
W23	NC
Y1	NC
Y2	I/O
Y3	I/O
Y4	GND
Y5	I/O
Y6	I/O
Y7	I/O
Y8	I/O
Y9	I/O
Y10	I/O
Y11	I/O
Y12	V _{CCA}
Y13	NC
Y14	I/O
Y15	I/O
Y16	I/O
Y17	I/O
Y18	I/O
Y19	I/O
Y20	GND
Y21	I/O
Y22	I/O
Y23	I/O

256-Pin FBGA			
Pin Number	A545X16A Function	A545X32A Function	A545X72A Function
E11	I/O	I/O	I/O
E12	I/O	I/O	I/O
E13	NC	I/O	I/O
E14	I/O	I/O	I/O
E15	I/O	I/O	I/O
E16	I/O	I/O	I/O
F1	I/O	I/O	I/O
F2	I/O	I/O	I/O
F3	I/O	I/O	I/O
F4	TMS	TMS	TMS
F5	I/O	I/O	I/O
F6	I/O	I/O	I/O
F7	V _{CCI}	V _{CCI}	V _{CCI}
F8	V _{CCI}	V _{CCI}	V _{CCI}
F9	V _{CCI}	V _{CCI}	V _{CCI}
F10	V _{CCI}	V _{CCI}	V _{CCI}
F11	I/O	I/O	I/O
F12	V _{CCA}	V _{CCA}	V _{CCA}
F13	I/O	I/O	I/O
F14	I/O	I/O	I/O
F15	I/O	I/O	I/O
F16	I/O	I/O	I/O
G1	NC	I/O	I/O
G2	I/O	I/O	I/O
G3	NC	I/O	I/O
G4	I/O	I/O	I/O
G5	I/O	I/O	I/O
G6	V _{CCI}	V _{CCI}	V _{CCI}
G7	GND	GND	GND
G8	GND	GND	GND
G9	GND	GND	GND
G10	GND	GND	GND
G11	V _{CCI}	V _{CCI}	V _{CCI}
G12	I/O	I/O	I/O
G13	GND	GND	GND
G14	NC	I/O	I/O
G15	V _{CCA}	V _{CCA}	V _{CCA}

256-Pin FBGA			
Pin Number	A545X16A Function	A545X32A Function	A545X72A Function
G16	I/O	I/O	I/O
H1	I/O	I/O	I/O
H2	I/O	I/O	I/O
H3	V _{CCA}	V _{CCA}	V _{CCA}
H4	TRST, I/O	TRST, I/O	TRST, I/O
H5	I/O	I/O	I/O
H6	V _{CCI}	V _{CCI}	V _{CCI}
H7	GND	GND	GND
H8	GND	GND	GND
H9	GND	GND	GND
H10	GND	GND	GND
H11	V _{CCI}	V _{CCI}	V _{CCI}
H12	I/O	I/O	I/O
H13	I/O	I/O	I/O
H14	I/O	I/O	I/O
H15	I/O	I/O	I/O
H16	NC	I/O	I/O
J1	NC	I/O	I/O
J2	NC	I/O	I/O
J3	NC	I/O	I/O
J4	I/O	I/O	I/O
J5	I/O	I/O	I/O
J6	V _{CCI}	V _{CCI}	V _{CCI}
J7	GND	GND	GND
J8	GND	GND	GND
J9	GND	GND	GND
J10	GND	GND	GND
J11	V _{CCI}	V _{CCI}	V _{CCI}
J12	I/O	I/O	I/O
J13	I/O	I/O	I/O
J14	I/O	I/O	I/O
J15	I/O	I/O	I/O
J16	I/O	I/O	I/O
K1	I/O	I/O	I/O
K2	I/O	I/O	I/O
K3	NC	I/O	I/O
K4	V _{CCA}	V _{CCA}	V _{CCA}

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
T3	I/O	I/O
T4	I/O	I/O
T5	I/O	I/O
T10	GND	GND
T11	GND	GND
T12	GND	GND
T13	GND	GND
T14	GND	GND
T15	GND	GND
T16	GND	GND
T17	GND	GND
T22	I/O	I/O
T23	I/O	I/O
T24	I/O	I/O
T25	NC *	I/O
T26	NC *	I/O
U1	I/O	I/O
U2	V _{CCI}	V _{CCI}
U3	I/O	I/O
U4	I/O	I/O
U5	I/O	I/O
U10	GND	GND
U11	GND	GND
U12	GND	GND
U13	GND	GND
U14	GND	GND
U15	GND	GND
U16	GND	GND
U17	GND	GND
U22	I/O	I/O
U23	I/O	I/O
U24	I/O	I/O
U25	V _{CCI}	V _{CCI}
U26	I/O	I/O
V1	NC *	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
V2	NC *	I/O
V3	I/O	I/O
V4	I/O	I/O
V5	I/O	I/O
V22	V _{CCA}	V _{CCA}
V23	I/O	I/O
V24	I/O	I/O
V25	NC *	I/O
V26	NC *	I/O
W1	I/O	I/O
W2	I/O	I/O
W3	I/O	I/O
W4	I/O	I/O
W5	I/O	I/O
W22	I/O	I/O
W23	V _{CCA}	V _{CCA}
W24	I/O	I/O
W25	NC *	I/O
W26	NC *	I/O
Y1	NC *	I/O
Y2	NC *	I/O
Y3	I/O	I/O
Y4	I/O	I/O
Y5	NC *	I/O
Y22	I/O	I/O
Y23	I/O	I/O
Y24	V _{CCI}	V _{CCI}
Y25	I/O	I/O
Y26	I/O	I/O

Note: *These pins must be left floating on the A54SX32A device.